

Carl Zeiss AG - EVO® 40 Series



Company

Carl Zeiss AG

Categories

Microscopy: Electron: SEM

Specifications

Resolution

3.0 nm @ 30 kV (SE and W)

2.0 nm @ 30 kV (SE and LaB6)

Acceleration Voltage

0.2 to 30 kV

Magnification

7 to 1,000,000x

Field of View

6 mm at the Analytical Working Distance (AWD)

X-ray Analysis

8.5 mm AWD and 35° take-off angle

OptiBeam® Modes

Resolution, Depth, Analysis, Large Field

Available Detectors
SE in HV - Everhart-Thornley
BSD in all modes - quadrant semiconductor diode

Chamber
310 mm (Ø) x 220 mm (h)

5-Axes Motorised Specimen Stage
X = 80 mm
Y = 80 mm
Z = 35 mm
T = 0° -90°
R = 360° (continuous)

Stage control by mouse or joystick and controlpanel

Image Processing
Resolution: Up to 3072 x 2304 pixel

Signal acquisition by integrating and averaging

Image Display
Single flicker-free XVGA monitor with SEM image displayed at 1024 x 768 pixel

System Control SmartSEM™** GUI operated by mouse and keyboard

Multilingual CONCISE GUI

Windows® XP operating system

Utility requirements
100 - 240V, 50 or 60 Hz single phase

No water cooling requirement